# PROCEEDINGS OF SPIE

# Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXIV

Gerald C. Holst Keith A. Krapels Editors

30 April – 2 May 2013 Baltimore, Maryland, United States

Sponsored and Published by SPIE

Volume 8706

Proceedings of SPIE 0277-786X, V. 8706

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Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXIV, edited by Gerald C. Holst, Keith A. Krapels, Proc. of SPIE Vol. 8706, 870601 · © 2013 SPIE CCC code: 0277-786X/13/\$18 · doi: 10.1117/12.2031917

Proc. of SPIE Vol. 8706 870601-1

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Author(s), "Title of Paper," in Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXIV, edited by Gerald C. Holst, Keith A. Krapels, Proceedings of SPIE Vol. 8706 (SPIE, Bellingham, WA, 2013) Article CID Number.

ISSN: 0277-786X ISBN: 9780819494979

Published by **SPIE** P.O. Box 10, Bellingham, Washington 98227-0010 USA Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445 SPIE.org

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### Contents

vii Conference Committee

#### SESSION 1 SYSTEMS

8706 02	Resampling in hyperspectral cameras as an alternative to correcting keystone in hardware, with focus on benefits for the optical design and data quality [8706-1] A. Fridman, G. Høye, T. Løke, Norsk Elektro Optikk (Norway)
8706 03	Infrared camera NUC and calibration: comparison of advanced methods [8706-2] F. Marcotte, P. Tremblay, V. Farley, Telops Inc. (Canada)

8706 04 An evaluation of image quality metrics aiming to validate long term stability and the performance of NUC methods [8706-3] T. Svensson, Swedish Defence Research Agency (Sweden)

#### SESSION 2 TESTING

8706 06	<b>Compensation for instrument anomalies in imaging infrared measurements</b> [8706-7] C. L. Dobbins, U.S. Army Aviation and Missile Research, Development and Engineering Ctr. (United States); J. A. Dawson, J. A. Lightfoot, W. D. Edwards, R. S. Cobb, A. R. Heckwolf, Dynetics, Inc. (United States)
8706 07	Characterization of domestic and foreign image intensifier tubes [8706-8] E. J. Bender, M. V. Wood, D. J. Hosek, S. D. Hart, U.S. Army RDECOM CERDEC NVESD (United States)
8706 08	Data analysis tools for imaging infrared technology within the ImageJ environment [8706-9] R. K. Rogers, W. D. Edwards, Dynetics, Inc. (United States); C. E. Waddle, C. L. Dobbins, S. B. Wood, U.S. Army AMRDEC (United States)
8706 09	An extended area blackbody for radiometric calibration [8706-10] J. LaVeigne, G. Franks, J. Singer, Santa Barbara Infrared, Inc. (United States); D. J. Arenas, Univ. of North Florida (United States); S. McHugh, Santa Barbara Infrared, Inc. (United States)
8706 0A	Active SWIR laboratory testing methodology [8706-11] C. M. Webb, Northrop Grumman Corp. (United States); S. White, B. Rich, SBIR (United States)
8706 OB	<b>Evaluation of dome-input geometry for pyroelectric detectors</b> [8706-39] J. Zeng, Utah State Univ. (United States); L. M. Hanssen, G. P. Eppeldauer, National Institute of Standards and Technology (United States)

#### SESSION 3 MODELING I

8706 OD	An investigation of image-based task performance prediction [8706-14]
	E. Jacobs, Univ. of Memphis (United States)

- 8706 OE Validating the time-dependent search parameter search model [8706-15] M. Friedman, U.S. Army RDECOM CERDEC NVESD (United States)
- 8706 OF Performance characterization of night vision equipment based on triangle orientation discrimination (TOD) methodology [8706-16]
   N. Laurent, C. Lejard, G. Deltel, PHOTONIS France S.A.S. (France); P. Bijl, TNO Behavioural and Societal Sciences (Netherlands)

#### SESSION 4 MODELING II

8706 0G	Sensor performance and atmospheric effects using NvThermIP/NV-IPM and
	PcModWin/MODTRAN models: a historical perspective (Invited Paper) [8706-18]
	D. Payne, J. Schroeder, Ontar Corp. (United States)

- 8706 0H Impact of the spectral nature of signatures on targeting with broadband imagers [8706-19] V. A. Hodgkin, U.S. Army RDECOM CERDEC NVESD (United States)
- 8706 01 **TOD characterization of the Gatekeeper electro-optical security system** [8706-20] G. Gosselink, H. Anbeek, Thales Nederland B.V. (Netherlands); P. Bijl, M. A. Hogervorst, TNO Behavioural and Societal Sciences (Netherlands)
- 8706 0J **Benchmarking image fusion system design parameters** [8706-21] C. L. Howell, U.S. Army RDECOM CERDEC NVESD (United States)
- 8706 OK **Quantitative evaluation of turbulence compensation** [8706-22] A. W. M. van Eekeren, K. Schutte, J. Dijk, P. B. W. Schwering, TNO (Netherlands)

#### SESSION 5 MODELING III

- What good is SWIR? Passive day comparison of VIS, NIR, and SWIR [8706-23]
   R. G. Driggers, Naval Research Lab. (United States); V. Hodgkin, U.S. Army RDECOM CERDEC NVESD (United States); R. Vollmerhausen, Univ. of Delaware (United States)
- Sensor model for space-based local area sensing of debris [8706-25]
   P. D. McCall, Florida International Univ. (United States); M. L. Naudeau, Air Force Research Lab. (United States); T. Farrell, Schafer Corp. (United States); M. E. Sorge, The Aerospace Corp. (United States); M. Adjouadi, Florida International Univ. (United States)

#### SESSION 6 MODELING IV

8706 ON	Producing a color target acquisition metric [8706-28]
	A. Asbag, R. Hayun, N. Gadot, R. Shama, S. R. Rotman, Ben-Gurion Univ. of the Negev
	(Israel)

- 8706 00 Image enhancement technology research for army applications [8706-29] P. B. W. Schwering, R. A. W. Kemp, K. Schutte, TNO (Netherlands)
- Multi-sensor fusion of electro-optic and infrared signals for high resolution visible images: part I [8706-42]
   X. Huang, Stevens Institute of Technology (United States); R. Netravali, Columbia Univ. (United States); H. Man, V. Lawrence, Stevens Institute of Technology (United States)

#### SESSION 7 TARGETS/BACKGROUNDS/ATM

- 8706 0Q Climatic data analysis for input to ShipIR [8706-30]
   D. A. Vaitekunas, W. R. Davis Engineering, Ltd. (Canada); Y. Kim, Korea Institute of Ocean Science & Technology (Korea, Republic of)
- 8706 OR Range and contrast imaging improvements using circularly polarized light in scattering environments [8706-31]
   J. D. van der Laan, College of Optical Sciences, The Univ. of Arizona (United States);
   D. A. Scrymgeour, S. A. Kemme, Sandia National Labs. (United States); E. L. Dereniak, College of Optical Sciences, The Univ. of Arizona (United States)
- 8706 0S Simulation of laser beam reflection at the sea surface modeling and validation [8706-32]
   F. Schwenger, E. Repasi, Fraunhofer-Institute for Optronics, System Technologies and Image Exploitation (Germany)
- 8706 0T Hyperspectral imaging spectro radiometer improves radiometric accuracy [8706-34]
   F. Prel, L. Moreau, R. Bouchard, ABB (Canada); R. D. Bullis, NAVAIR (United States); C. Roy, C. Vallières, L. Levesque, ABB (Canada)
- 8706 0U IR signature management for the modern navy [8706-33]
   D. A. Vaitekunas, W. R. Davis Engineering, Ltd. (Canada); Y. Kim, Korea Institute of Ocean Science & Technology (Korea, Republic of)

#### POSTER SESSION

8706 0V Simultaneous measurement of the thickness profile and refractive index distribution of silicon wafers [8706-36]

J. Park, Korea Research Institute of Standards and Science (Korea, Republic of); J. Jin, J. W. Kim, C. Kang, Korea Research Institute of Standards and Science (Korea, Republic of) and Univ. of Science and Technology (Korea, Republic of); J.-A. Kim, Korea Research Institute of Standards and Science (Korea, Republic of)

## 8706 0W Uncertainty evaluation of the geometrical thickness and refractive index of silicon wafers [8706-37]

J. Jin, Korea Research Institute of Standards and Science (Korea, Republic of) and Univ. of Science and Technology (Korea, Republic of); J. Park, Korea Research Institute of Standards and Science (Korea, Republic of); J. W. Kim, Korea Research Institute of Standards and Science (Korea, Republic of) and Univ. of Science and Technology (Korea, Republic of); J.-A. Kim, Korea Research Institute of Standards and Science (Korea, Republic of); C.-S. Kang, Korea Research Institute of Standards and Science (Korea, Republic and Univ. of Science and Technology (Korea, Republic of)

## 8706 0X Characterization of non-uniformity and bias-heating for uncooled bolometer FPA detectors using simulator [8706-38]

J. Lee, C.-M. Kyung, KAIST (Korea, Republic of)

Author Index

### **Conference Committee**

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2 Testing

Curtis M. Webb, Northrop Grumman Electronic Systems (United States) Alan Irwin, Santa Barbara Infrared, Inc. (United States)

- Modeling I
   Gisele Bennett, Georgia Institute of Technology (United States)
- 4 Modeling II James A. Dawson, Dynetics, Inc. (United States)
- Modeling III
   Ronald G. Driggers, U.S. Naval Research Laboratory (United States)
   Terrence S. Lomheim, The Aerospace Corporation (United States)
- Modeling IV
   Hector M. Reyes, Raytheon Company (United States)
   James A. Dawson, Dynetics, Inc. (United States)
- 7 Targets/Backgrounds/ATM
   Endre Repasi, Fraunhofer-Institut f
  ür Optronik, Systemtechnik und Bildauswertung (Germany)